Notice of References Cited Application/Control No. 10/724,570 Examiner Tod T. Van Roy Applicant(s)/Patent Under Reexamination TANAKA ET AL. Page 1 of 1

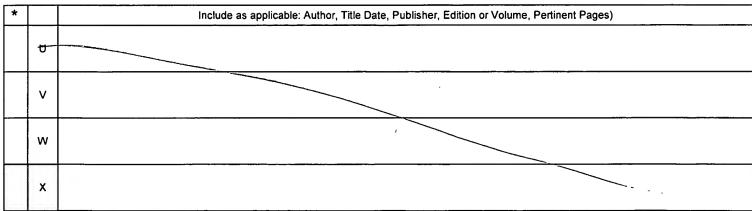
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,757,311	06-2004	Abe, Hiroaki	372/43.01
*	В	US-2001/0043632	11-2001	Ohya et al.	372/45
*	С	US-6,400,742	06-2002	Hatakoshi et al.	372/46.01
*	D	US-5,822,348	10-1998	Fujii, Hiroaki	372/45.01
	Ę,	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	Р					
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	Т					

NON-PATENT DOCUMENTS



*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.